



## P-Channel Enhancement MOSFET

### Features

- Drain-Source Breakdown Voltage  $V_{DSS}$  -50 V
- Drain-Source On-Resistance  
 $R_{DS(ON)} 5\Omega$ , at  $V_{GS} = -5.0V$ ,  $I_D = -0.1A$
- Continuous Drain Current at  $T_C=25^\circ C$   $I_D = -0.13A$
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free

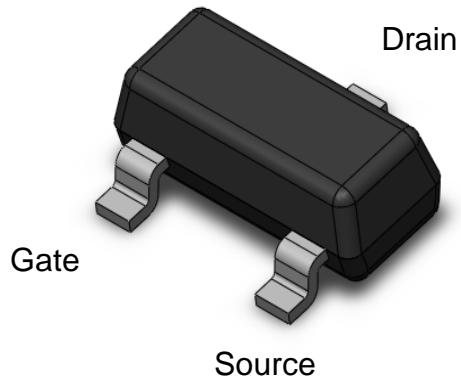
### Description

The CTL0015PS-R3 uses high performance Trench Technology to provide excellent  $R_{DS(ON)}$  and low gate charge which is suitable for most of the synchronous buck converter applications.

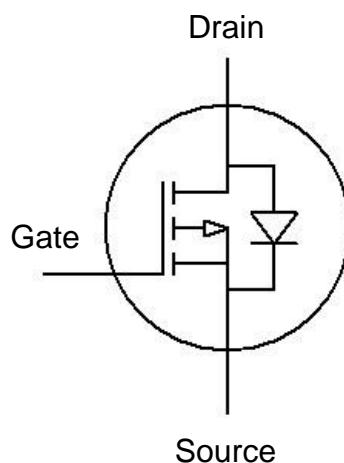
### Applications

- DC to DC Converter
- Load switching
- Battery

### Package Outline



### Schematic





CTL0015PS-R3

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### Absolute Maximum Rating at 25°C

| Symbol           | Parameters                           | Test Conditions | Min | Notes |
|------------------|--------------------------------------|-----------------|-----|-------|
| V <sub>DS</sub>  | Drain-Source Voltage                 | -50             | V   |       |
| V <sub>GS</sub>  | Gate-Source Voltage                  | ±20             | V   |       |
| I <sub>D</sub>   | Continuous Drain Current             | -0.13           | A   | 1     |
| I <sub>DM</sub>  | Pulsed Drain Current                 | -0.52           | A   | 1     |
| P <sub>D</sub>   | Total Power Dissipation              | 0.225           | W   | 2     |
| T <sub>STG</sub> | Storage Temperature Range            | -55 to 150      | °C  |       |
| T <sub>J</sub>   | Operating Junction Temperature Range | -55 to 150      | °C  |       |

### Thermal Characteristics

| Symbol            | Parameters                                     | Test Conditions | Min | Typ | Max | Units | Notes |
|-------------------|--|-----------------|-----|-----|-----|-------|-------|
| R <sub>θJA4</sub> | Thermal Resistance<br>Junction-Ambient (t=10s) |                 | --  | 175 | --  | °C /W | 1,4   |



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Electrical Characteristics  $T_A = 25^\circ\text{C}$  (unless otherwise specified)

## Static Characteristics

| Symbol            | Parameters                     | Test Conditions                               | Min | Typ | Max  | Units | Notes |
|-------------------|--------------------------------|---|-----|-----|------|-------|-------|
| B <sub>VDSS</sub> | Drain-Source Breakdown Voltage | V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA | -50 | -   | -    | V     |       |
| I <sub>DSS</sub>  | Drain-Source Leakage Current   | V <sub>DS</sub> = -25V, V <sub>GS</sub> = 0V  | -   | -   | -0.1 | μ A   |       |
| I <sub>DS</sub>   | Drain-Source Leakage Current   | V <sub>DS</sub> = -50V, V <sub>GS</sub> = 0V  |     |     | 15   | μ A   |       |
| I <sub>GSS</sub>  | Gate-Source Leakage Current    | V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V  | -   | -   | ±60  | μ A   |       |

## On Characteristics

| Symbol              | Parameters                    | Test Conditions   | Min  | Typ | Max  | Units | Notes |
|---------------------|-------------------------------|---|------|-----|------|-------|-------|
| R <sub>DSON</sub>   | Drain-Source On-Resistance    | V <sub>GS</sub> = -5.0V, I <sub>D</sub> = -100mA            | -    | 5.0 | 10   | Ω     | 3     |
| V <sub>GS(th)</sub> | Gate-Source Threshold Voltage | V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = -250μA | -0.8 | --- | -2.0 | V     | 3     |

## Dynamic Characteristics

| Symbol           | Parameters                   | Test Conditions  | Min | Typ | Max | Units | Notes |
|------------------|------------------------------|--|-----|-----|-----|-------|-------|
| C <sub>iss</sub> | Input Capacitance            | V <sub>GS</sub> = 0V,<br>V <sub>DS</sub> = -5V<br>f=1MHz | -   | 29  | -   | pF    |       |
| C <sub>oss</sub> | Output Capacitance           |  | -   | 11  | -   |       |       |
| C <sub>rss</sub> | Reverse Transfer Capacitance |  | -   | 4.8 | -   |       |       |

## Switching Characteristics

| Symbol              | Parameters          | Test Conditions   | Min | Typ | Max | Units | Notes |
|---------------------|---------------------|---|-----|-----|-----|-------|-------|
| T <sub>D(ON)</sub>  | Turn-On Delay Time  | V <sub>DS</sub> = -15V ,<br>R <sub>G</sub> = 15Ω,<br>I <sub>D</sub> = -2.5A | -   | 2.5 | -   | ns    |       |
| T <sub>R</sub>      | Rise Time           |   | -   | 1.0 | -   |       |       |
| T <sub>D(OFF)</sub> | Turn-Off Delay Time |   | -   | 16  | -   |       |       |
| T <sub>F</sub>      | Fall Time           |   | -   | 8.0 | -   |       |       |
| Q <sub>G</sub>      | Total Gate Charge   | V <sub>DS</sub> = -15V ,  | -   | 0.6 | -   | nC    |       |



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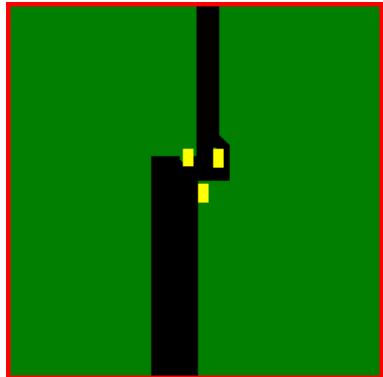
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### Drain-Source Diode Characteristics

| Symbol          | Parameters                    | Test Conditions                             | Min | Typ  | Max  | Units | Notes |
|-----------------|-------------------------------|---|-----|------|------|-------|-------|
| V <sub>SD</sub> | Body Diode Forward Voltage    | V <sub>GS</sub> = 0V, I <sub>D</sub> = -3.1 | -   | -2.5 | -    | V     |       |
| I <sub>SD</sub> | Body Diode Continuous Current |   | -   | -    | -130 | mA    | 1     |

Note:

1. The power dissipation is limited by 150°C junction temperature.
2. Device mounted on a glass-epoxy board



FR-4  
25.4 x 25.4 mm .  
2 Oz Copper

Actual Size

3. The data tested by pulsed , pulse width  $\leq 300\mu\text{s}$  , duty cycle  $\leq 2\%$
4. Thermal Resistance follow JESD51-3.



## Typical Characteristic Curves

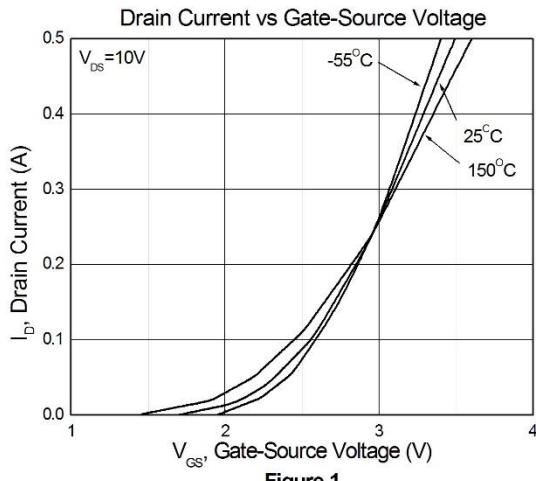


Figure 1

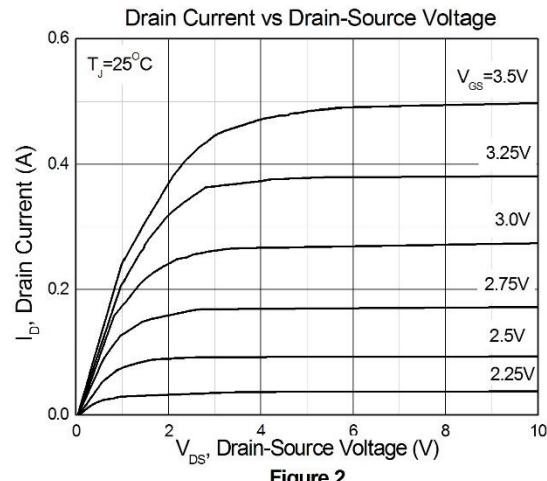


Figure 2

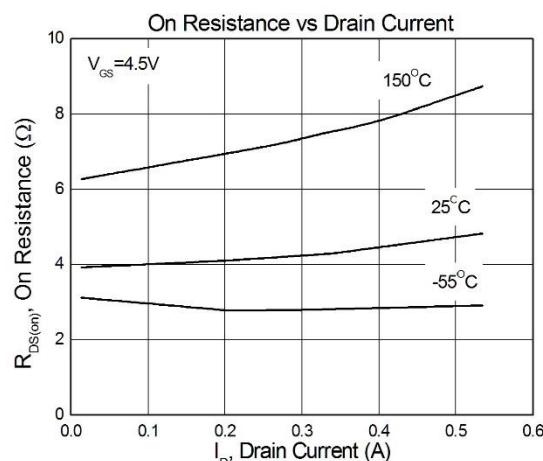


Figure 3

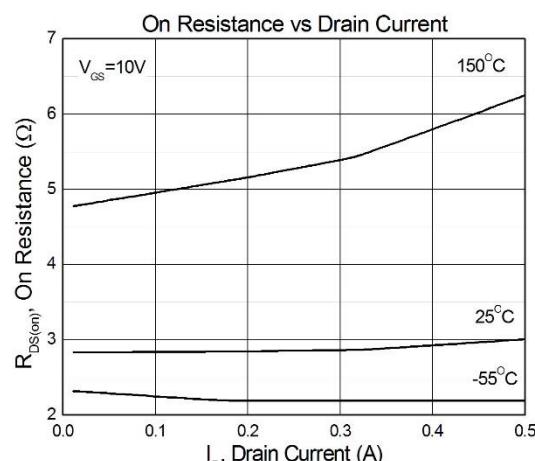


Figure 4

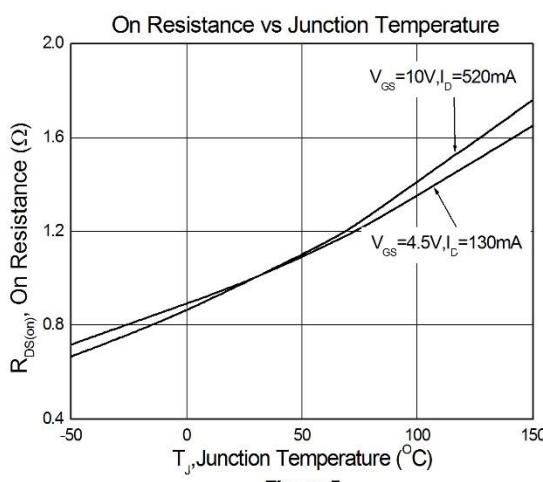


Figure 5

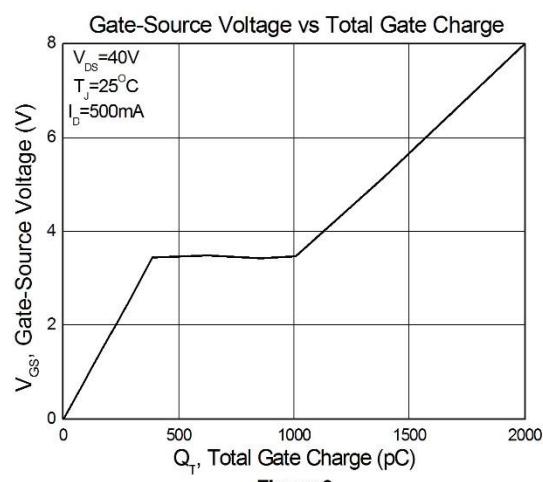


Figure 6



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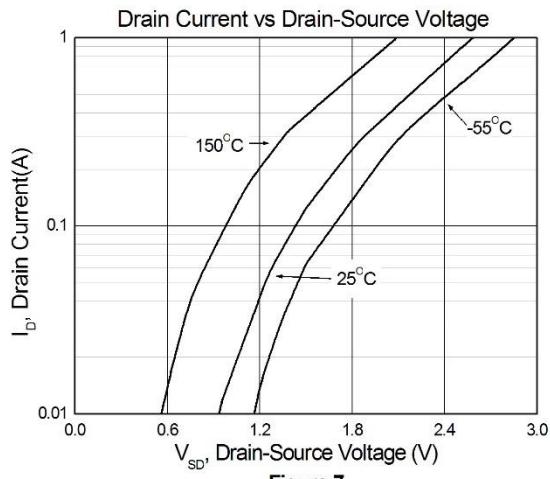


Figure 7



## Test Circuits & Waveforms

Figure 8: Gate Charge Test Circuit

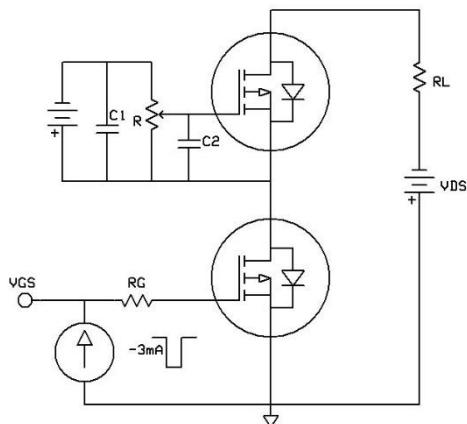


Figure 9: Gate Charge Waveform

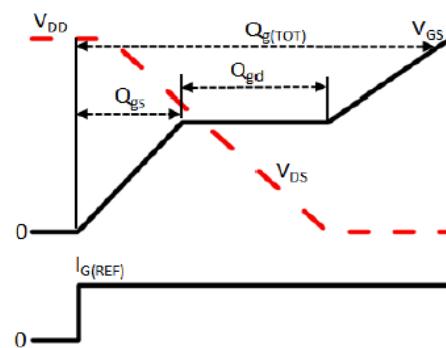


Figure 10: Switching Time Test Circuit

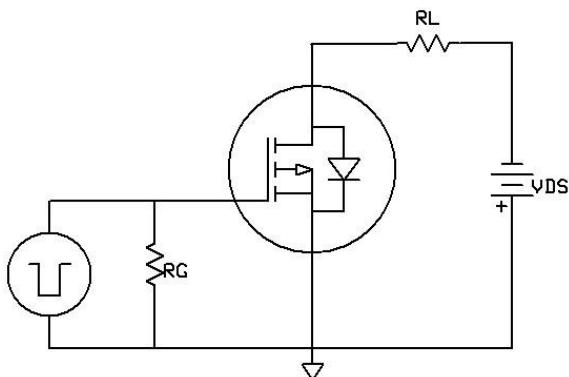
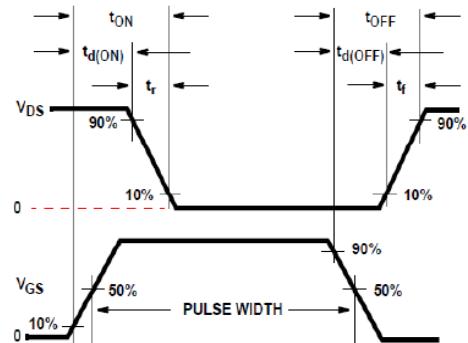
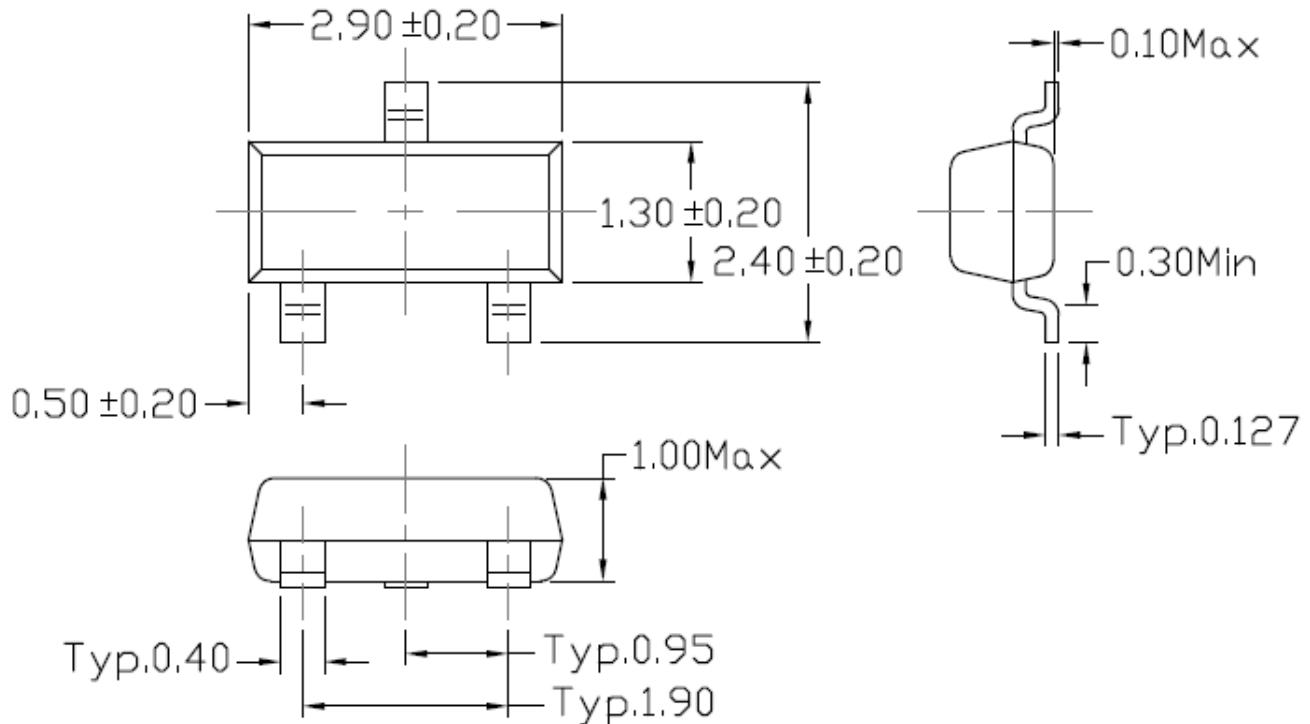
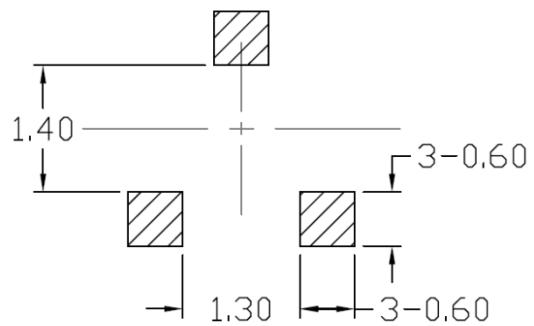


Figure 111: Switching Time Waveform



**Package Dimension (SOT-23)**

Note: Dimensions in mm

**Recommended pad layout for surface mount leadform**

Note: Dimensions in mm

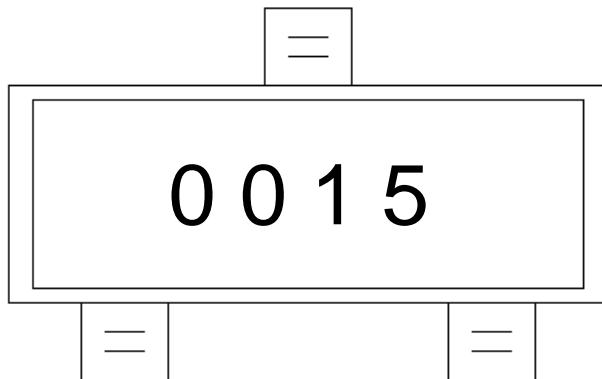


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### Marking Information



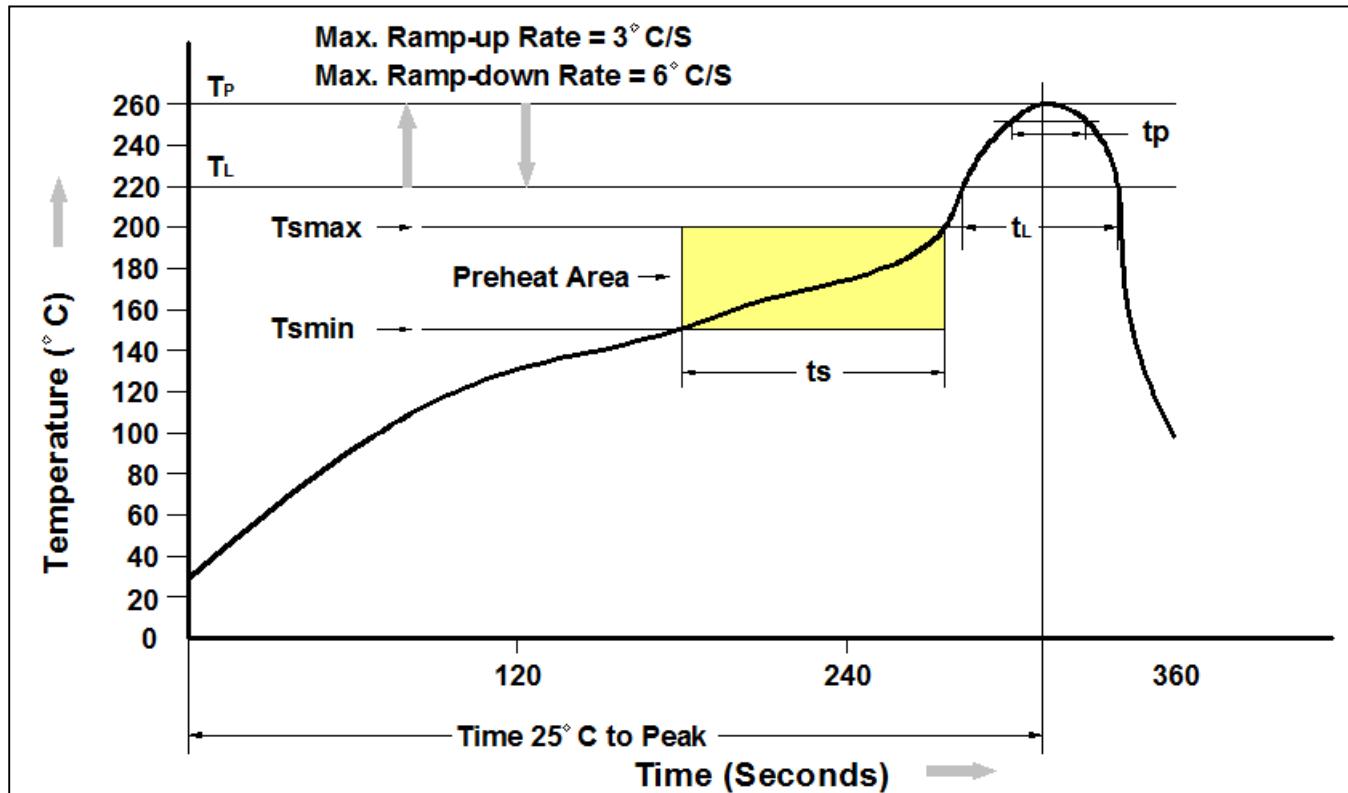
0015: Device Number

### Ordering Information

| Part Number  | Description | Quantity |
|--------------|-------------|----------|
| CTL0015PS-R3 | SOT-23 Reel | 3000 pcs |



## Reflow Profile



| Profile Feature   | Pb-Free Assembly Profile |
|---|--------------------------|
| Temperature Min. (T <sub>smin</sub> )                                 | 150°C                    |
| Temperature Max. (T <sub>smax</sub> )                                 | 200°C                    |
| Time (t <sub>s</sub> ) from (T <sub>smin</sub> to T <sub>smax</sub> ) | 60-120 seconds           |
| Ramp-up Rate (t <sub>L</sub> to t <sub>P</sub> )                      | 3°C/second max.          |
| Liquidous Temperature (T <sub>L</sub> )                               | 217°C                    |
| Time (t <sub>L</sub> ) Maintained Above (T <sub>L</sub> )             | 60 – 150 seconds         |
| Peak Body Package Temperature   | 260°C +0°C / -5°C        |
| Time (t <sub>P</sub> ) within 5°C of 260°C                            | 30 seconds               |
| Ramp-down Rate (T <sub>P</sub> to T <sub>L</sub> )                    | 6°C/second max           |
| Time 25°C to Peak Temperature   | 8 minutes max.           |



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